

FAST - (09-740634.wsp) File View Edit Tools Window Help

(286) 324/763.ccls.
(44) 324/763.ccls. and multiplexer
(4) "1088239"
(7872) schmid
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(41) 3849872.URPN.
(12) 3801910.URPN.
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DB: USPAT.USPQ.PUB

Default operator: OR

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☒ Highlight all hits initially

US 5321277 A 19940614 8 Multi-chip module testing 257/48 257/390; 365/200; Sparks, Steve al.

US 5097205 A 19920317 8 IC chip test circuit for high frequency integrated circuits 324/763 324/73.1; 327/564 Toyota, Nobu

US 3801910 A 19740402 6 EXTERNALLY ACCESSING MECHANICAL DIFFICULT TO ACCESS CIRCUIT NODES USING PHOTO-RESPONSIVE CONDUCTORS IN INTEGRATED 324/752 257/461 Quinn, Huber

US 3849872 A 19741126 6 CONTACTING INTEGRATED CIRCUIT CHIP TERMINAL THROUGH THE WAFER KERF 438/17 257/734; 324/158.1; Hubscher, Et

US 4982403 A 19910101 8 Electrical circuit testing device and circuit comprising the said device 714/732 Du Chene, Ar al.

US 5895978 A 19990420 8 High density signal multiplexing interposer 257/786 257/678; 257/698; Palagonia, Michael

US 6127729 A 20001003 17 Semiconductor chip with corner electrode terminals and detecting wiring for defect inspection 257/736 257/208; 257/210; Fukuda, Kazu

US 4908576 A 19900313 45 System for printed circuit board testing 714/726 324/73.1; 324/754; Jackson, Dar

US 6448783 B1 20020910 17 Method of inspecting semiconductor chip with projecting electrodes for defects 324/537 324/765 Fukuda, Kazu

US 6184569 B1 20010206 14 Semiconductor chip inspection structures 257/620 257/48; 257/E23.151 Fukuda, Kazu

US 6362523 B1 20020326 8 Semiconductor device 257/723 257/528; 257/E23.142; Fukuda, Kazu

US 4724379 A 19880209 7 Relay multiplexing for circuit testers 307/115 324/158.1; 714/734 Hoffman, Mar

EP 533589 A1 19930324 17 A semiconductor device. 257/203; 257/786; OGAWA, JUNJI

US 5418470 A 19950523 6 Analog multi-channel probe system 324/763 324/158.1; 714/733 Dagostino, T et al.

US 5712858 A 19980127 12 Test methodology for exceeding tester pin count for an asic device 714/724 Godiwala, Ni Dhiroobhai e

Ready

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